

## AMENDMENTS TO THE SPECIFICATION

Please amend the paragraph starting at line 9 on page 1 as follows:

This application is related to U.S. Patent Application Serial Number 10/824,703 [[\_\_\_\_\_]] by B. West et al., filed on [[\_\_\_\_\_]] April 14, 2004, entitled "Configurable Tester with Diagnostic Capability," ~~with Attorney Docket No. NPT-65.0391,~~ assigned to the assignee of the present invention, and hereby incorporated by reference in its entirety.

Please amend the abstract as indicated on the following page:

A test apparatus including a means for sending a first test pattern to a device under test (DUT), where the first test pattern is a part of a planned sequence of tests, and further including a means for evaluating the test results received from the DUT, and a method of testing are described. ~~A first test pattern is sent to a device under test (DUT). The first test pattern part of a planned sequence of tests. Test results received from the DUT are evaluated.~~ The test results may include anomalous data indicative of a defect in the DUT. If so, a second test pattern that is not part of the planned sequence of tests is selected. The second test pattern is selected based on a diagnosis of the anomalous data by the test apparatus.